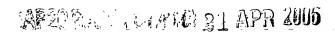
## 10/576486

Customer No. 28289

Application No. Not Yet Assigned Paper Dated: April 21, 2006

In Reply to USPTO Correspondence of N/A

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## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.

Not Yet Assigned

**Applicants** 

Chie ISHIKAWA et al.

Filed

Concurrently Herewith

Title

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INSPECTING SURFACE DEFECT

International Application

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## MAIL STOP PCT

Commissioner for Patents P. O. Box 1450 Alexandria, VA 22313-1450

## PRELIMINARY AMENDMENT

Sir:

Prior to initial examination, please amend the above-identified patent application

as follows:

Amendments to the Claims begin on page 2 of this paper.

Amendments to the Abstract begin on page 7 of this paper.

Remarks begin on page 8 of this paper.